



DOCUMENT CHANGE REQUEST

DCR number 339 Changes required for: General
Date: 2007/06/19 Date sent: 2007/06/19
Status: IMPLEMENTED

Originator: S Thacker
Organisation: ESA/ESTEC

Title: Resistors Fixed Chip Thick Film Based on Type CHP

Number: 4001/026 Issue: 1

Other documents affected:

Page:

see below & attached

Paragraph:

see below & attached

Original wording:

Proposed wording:

See also attached mark-up for details.

Page 7 Table 1(a)

For Variant 05 correct the Critical Resistance value to be "112.5kohm" (was "112kohm")

Page 7 Table 1(b)

For Rated dissipation:

- correct Variant 03 style to be "1206" (was "1216")
- correct the Maximum ratings Units to be in "mW" (was in "W") e.g. Variant 01 to be "100mW" (was "0.1W")

For Insulation Voltage amend the symbol to be "UI" (was "Ui")

Page 8 Figure 1

Amend figure so that the "0" is positioned against the Y-axis (=0%)(no minimum value is specified for the X-axis)

Page 12 Para 4.5.3

Correct the example to read "400102601B (was "4001xxx01B")

Correct the Detail specification reference to be "4001026" (was "4001xxx")



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Page 15 Table 6

Correct No.5 Voltage Proof Conditions to read "UI" (was "Ui")

Complete No.6 Solderability Test Methods and Conditions to read "Para. 9.9 Procedure I" (was "Para. 9.9")

Page 16 Table 6

Amend No.11 Climatic Sequence so that the "Insulation Resistance" inspection follows "Resistance Change" rather than being before it.

Page 17 Table 6 Notes

Correct note 3 to read "UI" (was "Ui").

Amend notes 4, 5, 6, 7 to remove the inner set of redundant parentheses for each limit value equation.

e.g. Note 4 to be " +/-(-0.5 + 0.05ohm x 100/Rn)% " (was " +/-(-0.5 + (0.05ohm x 100/Rn))% "

Justification:

All changes are editorial amendments only done for the purposes of correction, consistency and clarification.

Attachments:

DCR339att.pdf, DCR_Attachment_for_4001026.pdf, null

Modifications:

N/A

Approval signature:

Date signed:

2007-06-19



Pages 1 to 18

RESISTOR, FIXED, CHIP, THICK FILM

BASED ON TYPE CHP

ESCC Detail Specification No. 4001/026

Time

| | |
|-------------------|--------------|
| Issue / 2 Draft A | January 2007 |
|-------------------|--------------|





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| DCR No. | CHANGE DESCRIPTION |
|---------|---|
| | Specification updated to incorporate editorial changes per DCR. |

see
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w No (339)

| Variant | Style (Note 1) | Resistance Range R_n (Note 2) | | Tolerance (\pm %) (Note 2) | Temperature Coefficient TC ($\pm 10^{-6}/^{\circ}\text{C}$) (Note 2) | Critical Resistance (k Ω) | Weight max (g) |
|---------|----------------|---------------------------------|-------------------|-------------------------------|--|-----------------------------------|----------------|
| | | Min (Ω) | Max (M Ω) | | | | |
| 05 | 2512 | 1 | 10 | 1, 2, 5 | 100, 200 | 112 | 0.042 |

NOTES:

1. See Figure 2
- 2.

112.5

| Resistance (Ω) | Value Series | Available Tolerance (\pm %) | Available Temperature Coefficient ($\pm 10^{-6}/^{\circ}\text{C}$) |
|---------------------------|--|--------------------------------|--|
| $1 \leq R_n < 10$ | Any value in the resistance range to 3 significant figures | 2, 5 | 200 |
| $10 \leq R_n < 1\text{M}$ | | 1, 2, 5 | 100, 200 |
| $R_n \geq 1\text{M}$ | | 2, 5 | 200 |

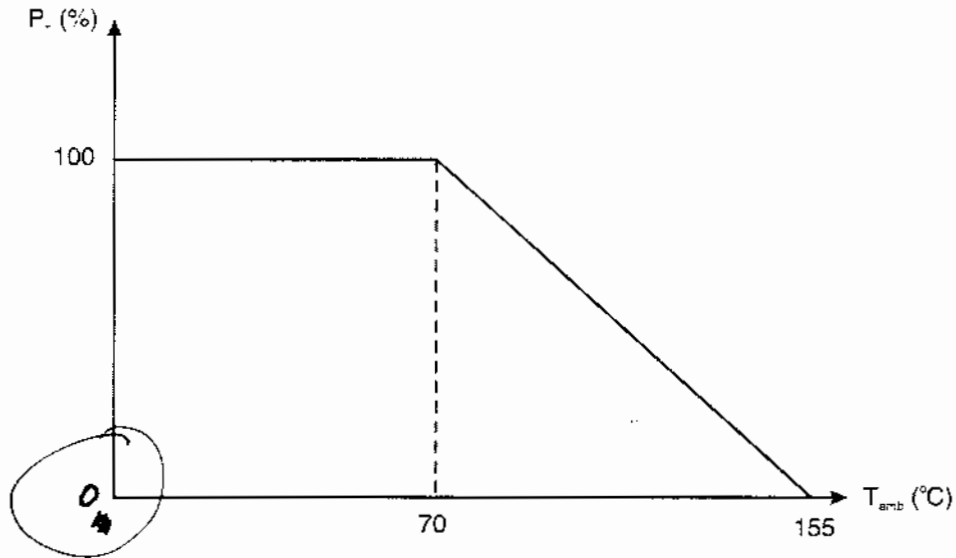
Table 1(b) - MAXIMUM RATINGS

| No. | Characteristics | Variant | Style | Symbol | Maximum Rating | Unit | Remarks |
|-----|-----------------------------|----------------------------|--|-----------|--|--------------------|-----------|
| 1 | Rated Dissipation | 01 02 03 04 05 | 0603 0805 1216 1206 2010 2512 | P_n | 0.1 100 0.2 200 0.25 250 0.5 500 0.8 800 | W mW | Note 1 |
| 2 | Limiting Element Voltage | 01 02 03 04 05 | 0603 0805 1206 2010 2512 | U_L | 50 100 200 300 300 | V | - |
| 3 | Rated Voltage | All | All | U_R | $\sqrt{P_n \times R_n}$ | V | Note 2 |
| 4 | Insulation Voltage | 01 02 03 04 05 | 0603 0805 1206 2010 2512 | U_I | 100 200 300 300 300 | V | - |
| 5 | Operating Temperature Range | All | All | T_{op} | -55 to +155 | $^{\circ}\text{C}$ | T_{amb} |
| 6 | Storage Temperature Range | All | All | T_{stg} | -55 to +155 | $^{\circ}\text{C}$ | - |
| 7 | Soldering Temperature | All | All | T_{sol} | +260 | $^{\circ}\text{C}$ | Note 3 |

NOTES:

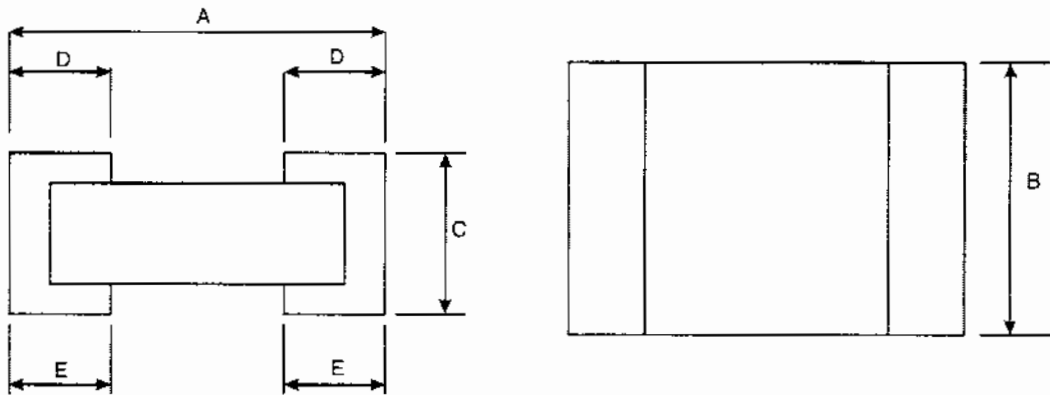
1. At $T_{amb} \leq +70^{\circ}\text{C}$. For derating at $T_{amb} > +70^{\circ}\text{C}$, see Figure 1.
2. Shall never exceed Limiting Element Voltage. R_n = rated resistance.
3. Duration 10 seconds maximum.

FIGURE 1 - PARAMETER DERATING INFORMATION



Rated Dissipation versus Temperature

FIGURE 2 - PHYSICAL DIMENSIONS



| Variant | Style | Dimensions (mm) | | | | | | | |
|---------|-------|-----------------|------|------|------|------|------|------|------|
| | | A | | B | | C | | D, E | |
| | | Min | Max | Min | Max | Min | Max | Min | Max |
| 01 | 0603 | 1.36 | 1.68 | 0.72 | 0.98 | 0.38 | 0.53 | 0.25 | 0.51 |
| 02 | 0805 | 1.75 | 2.07 | 1.14 | 1.4 | 0.38 | 0.53 | 0.25 | 0.51 |
| 03 | 1206 | 2.89 | 3.21 | 1.47 | 1.73 | 0.38 | 0.53 | 0.25 | 0.51 |
| 04 | 2010 | 4.92 | 5.24 | 2.41 | 2.67 | 0.5 | 0.63 | 0.25 | 0.64 |
| 05 | 2512 | 6.19 | 6.51 | 2.93 | 3.32 | 0.5 | 0.63 | 0.25 | 0.64 |

4.5.3 ESCC Component Number

The ESCC Component Number shall be constituted and marked as follows:

Example : 4001~~xxx~~01B

- Detail Specification Reference : 4001~~xxx~~
- Component Type Variant Number : 01 (as required)
- Testing Level (B or C, as applicable)

4.5.4 Traceability Information

Each component shall be marked in respect of traceability information in accordance with the requirements of ESCC Basic Specification No. 21700.

4.6 ELECTRICAL MEASUREMENTS

4.6.1 Electrical Measurements at Room Temperature

The parameters to be measured at room temperature are scheduled in Table 2. Unless otherwise specified, measurements shall be performed at $T_{amb}=+22\pm 3^{\circ}\text{C}$.

4.6.2 Electrical Measurements at High and Low Temperatures

The parameters to be measured at high and low temperatures are scheduled in Table 3.

The distribution of the sample shall be as follows:

- 1/3 with lowest resistance value
- 1/3 with highest resistance value
- 1/3 with median resistance value or the critical resistance value if procured

of the procured range.

4.6.3 Circuits for Electrical Measurements (Figure 4)

Not applicable.

4.7 BURN-IN TESTS

4.7.1 Parameter Drift Values

The parameter drift values applicable to Burn-in are as specified in Table 4 of this specification. Unless otherwise stated, measurements shall be performed at $T_{amb}=+22\pm 3^{\circ}\text{C}$. The parameter drift values (Δ) applicable to the parameters scheduled shall not be exceeded. In addition to these drift value requirements for a given parameter, the appropriate limit values specified in Table 2 shall not be exceeded.

4.7.2 Conditions for Burn-in

The requirements for Burn-in are specified in Section 7 of ESCC Generic Specification No. 4001. The conditions for Burn-in shall be as specified in Table 5 of this specification.

After 168 (²⁴~~12~~-0) hours, the resistors shall be removed from the chamber and allowed to cool under normal atmospheric conditions for a minimum of 4 hours. They shall then be visually examined. There shall be no evidence of damage and marking shall still be legible.

Table 6 - MEASUREMENTS AND INSPECTIONS ON COMPLETION OF ENVIRONMENTAL TESTS AND AT INTERMEDIATE POINTS AND ON COMPLETION OF ENDURANCE TESTING

| No. | ESCC Generic Spec. No. 4001 | | Measurements and Inspections | | Symbol | Limits | | Unit | |
|---------------------------|--|---|--|---|------------------|------------------|---------------|----------------------|----------|
| | Environmental and Endurance Tests (Note 1) | Test Methods and Conditions | Identification | Conditions | | Min | Max | | |
| 01 | Overload | Para. 9.1 and Paras 4.2.2 and 4.2.4 of this spec. | <u>Initial Measurements</u> | Table 2 Item 1 After a recovery period of 1-2 hrs No evidence of damage and marking legible | R_A | Record Values | | Ω | |
| | | | Chart IV Resistance | | | | | | |
| | | | <u>Final Measurements</u> | Table 2 item 1 | R_A | Table 2 Item 1 | | Ω | |
| | | | Visual Examination | | | | | | |
| | | Chart II Resistance | Table 2 Item 1 | $\Delta R_A/R_A$ | Note 4 | | % | | |
| | | Chart IV Resistance Change | | | | | | | |
| 02 | Seal Test (Hermetically Sealed only) | Para. 9.3 | Not applicable | - | - | - | - | - | |
| 03 | Insulation Resistance (Insulated only) | Para. 9.6 | <u>Final Measurements</u> Insulation Resistance | Para. 9.6.2 of ESCC 4001 (Note 2) | R_i | 1000 | - | M Ω | |
| 04 | Temperature Coefficient | Para. 9.7 Procedure I | Temperature Coefficient | Para. 9.5.1 of ESCC 4001 | TC | -100 -200 | +100 +200 | 10 ⁻⁶ /°C | |
| 05 | Voltage Proof | Para. 9.8.2 | <u>During test</u> | 1.4 x 100 ^{UT} for 60 ± 5 sec (Note 3) | - | - | - | - | |
| | | | Visual Examination | No breakdown or flashover | - | - | - | - | |
| 06 | Solderability | Para. 9.9 <i>Procedure I</i> | <u>Initial Measurements</u> | After Drying Table 2 item 1 24 ± 4hrs after soldering | R_A | Record Values | | Ω | |
| | | | Resistance | | | | | | |
| | | | <u>Final Measurements</u> | Table 2 Item 1 | $\Delta R_A/R_A$ | Note 5 | | % | |
| Resistance Change | | | | | | | | | |
| 07 | Robustness of Terminations | Para. 9.10.2 | - | After Mounting | | | | | |
| | | | Adhesion | <u>Initial Measurements</u> | Table 2 Item 1 | R_A | Record Values | | Ω |
| | | | | Resistance | | | | | |
| | | | | <u>Final Measurements</u> | Table 2 Item 1 | $\Delta R_A/R_A$ | Note 5 | | % |
| | | Resistance Change | | | | | | | |
| | | Visual Examination | No damage, lifting, cracking or dry joints | - | - | - | | | |
| | | Bend Strength of End Plate Facing | <u>Initial Measurements</u> | Table 2 Item 1 | R_A | Record Values | | Ω | |
| | | | Resistance | | | | | | |
| <u>Final Measurements</u> | Table 2 Item 1 | | $\Delta R_A/R_A$ | Note 5 | | % | | | |
| Resistance Change | | | | | | | | | |
| Visual Examination | No damage, lifting, cracking or dry joints | - | - | - | | | | | |

| No. | ESCC Generic Spec. No. 4001 | | Measurements and Inspections | | Symbol | Limits | | Unit |
|-----------------------|--|--|---|--|------------------|---------------|-----|------------|
| | Environmental and Endurance Tests (Note 1) | Test Methods and Conditions | Identification | Conditions | | Min | Max | |
| 08 | Resistance to Soldering Heat | Para. 9.11 Procedure I | <u>Initial Measurements</u> Resistance | After Drying Table 2 Item 1 | R_A | Record Values | | Ω |
| | | | <u>Final Measurements</u> Visual Examination | No evidence of damage and marking legible | - | - | - | |
| | | | Resistance Change | Table 2 Item 1 | $\Delta R_A/R_A$ | Note 4 | % | |
| 09 | Rapid Change of Temperature | Para. 9.12 | <u>Initial Measurements</u> Resistance | Table 2 Item 1 | R_A | Record Values | | Ω |
| | | | <u>Final Measurements</u> Visual Examination | After a recovery period of 1-2 hrs No evidence of damage | - | - | - | |
| | | | Resistance Change | Table 2 Item 1 | $\Delta R_A/R_A$ | Note 5 | % | |
| 10 | Vibration | Para. 9.13 and Paras 4.2.4 and 4.2.5 of this spec. | Not applicable | - | - | - | - | - |
| 11 | Climatic Sequence | Para. 9.14 Procedure I | <u>Initial Measurements</u> Resistance | After Drying Table 2 Item 1 | R_A | Record Values | | Ω |
| | | | <u>Final Measurements</u> Visual Examination | Following completion of DC load test and after a recovery period of 1-2 hrs No evidence of damage and marking legible | - | - | - | |
| | | | Insulation Resistance | Para. 9.6 of ESCC 4001 (Note 2) | R_i | 1000 | - | M Ω |
| Resistance Change | Table 2 Item 1 | $\Delta R_A/R_A$ | Note 6 | % | | | | |
| 12 | Operating Life | Para. 9.15 Chart IV | <u>Initial Measurements</u> Resistance | Table 2 Item 1 | R_A | Record Values | | Ω |
| | | | <u>Intermediate Measurements</u> (1000 hrs) | After a recovery period of 1-2 hrs | - | - | - | |
| | | | Visual Examination | No evidence of damage | - | - | - | |
| | | | Resistance Change | Table 2 Item 1 | $\Delta R_A/R_A$ | Note 6 | % | |
| | | | <u>Final Measurements</u> (2000 hrs) | After a recovery period of 1-2 hrs | - | - | - | |
| | | | Visual Examination | No evidence of damage | - | - | - | |
| Resistance Change | Table 2, Item 1 | $\Delta R_A/R_A$ | Note 7 | % | | | | |
| Insulation Resistance | Para. 9.6 of ESCC 4001 (Note 2) | R_i | 1000 | - | M Ω | | | |

| No. | ESCC Generic Spec. No. 4001 | | Measurements and Inspections | | Symbol | Limits | | Unit |
|-----|--|-----------------------------|---|--|--|---|---|------|
| | Environmental and Endurance Tests (Note 1) | Test Methods and Conditions | Identification | Conditions | | Min | Max | |
| | | Para. 9.15 Chart V | <u>Initial Measurements</u> Resistance <u>Final Measurements</u> (1000 hrs) Visual Examination Resistance Change Insulation Resistance | Table 2 Item 1 After a recovery period of 1 -2 hrs No evidence of damage Table 2 Item 1 Para. 9.6 of ESCC 4001 (Note 2) | R_A - $\Delta R_A/R_A$ R_i | Record Values - Note 6 1000 - | Ω - % $M\Omega$ | |
| 13 | High Temperature Storage | Para. 9.16 | <u>Initial Measurements</u> Resistance <u>Intermediate</u> <u>Measurements</u> (1000 hrs) Visual Examination Resistance Change <u>Final Measurements</u> (2000 hrs) Visual Examination Resistance Change Insulation Resistance | Table 2 Item 1 After a recovery period of 1-2 hrs No evidence of damage Table 2 Item 1 After a recovery period of 1-2 hrs No evidence of damage Table 2 Item 1 Para. 9.6 of ESCC 4001 (Note 2) | R_A - $\Delta R_A/R_A$ - $\Delta R_A/R_A$ R_i | Record Values - Note 6 - - Note 7 1000 - | Ω - % - % $M\Omega$ | |
| 14 | Permanence of Marking | Para. 9.19 | - | - | - | - | - | - |

NOTES:

1. The tests in this Table refer to either Chart IV or V and shall be used as applicable.

2. Test Voltage: $V_T = 100V$

3. For value of U_i see Table 1(b) Item 4.

4. $\Delta R_A/R_A$ limit: $\pm(0.5 + 0.05\Omega \times 100/R_n)\%$

5. $\Delta R_A/R_A$ limit: $\pm(0.25 + 0.05\Omega \times 100/R_n)\%$

6. $\Delta R_A/R_A$ limit: $\pm(1 + 0.05\Omega \times 100/R_n)\%$

7. $\Delta R_A/R_A$ limit: $\pm(1.5 + 0.05\Omega \times 100/R_n)\%$

$\leftarrow \pm(0.5 + 0.05\Omega \times 100/R_n)\%$
 $\leftarrow \pm(0.25 + 0.05\Omega \times 100/R_n)\%$
 $\leftarrow \pm(1 + 0.05\Omega \times 100/R_n)\%$
 $\leftarrow \pm(1.5 + 0.05\Omega \times 100/R_n)\%$

U_i

MARV-up border

S.T.



Pages 1 to 18

RESISTOR, FIXED, CHIP, THICK FILM

BASED ON TYPE CHP

ESCC Detail Specification No. 4001/026

June

| | |
|-------------------|--------------|
| issue / 2 Draft A | January 2007 |
|-------------------|--------------|



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| DCR No. | CHANGE DESCRIPTION |
|---------|---|
| | Specification updated to incorporate editorial changes per DCR. |

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No.

| Variant | Style (Note 1) | Resistance Range R_n (Note 2) | | Tolerance (\pm %) (Note 2) | Temperature Coefficient TC ($\pm 10^{-6}/^{\circ}\text{C}$) (Note 2) | Critical Resistance (k Ω) | Weight max (g) |
|---------|----------------|---------------------------------|-------------------|-------------------------------|--|-----------------------------------|----------------|
| | | Min (Ω) | Max (M Ω) | | | | |
| 05 | 2512 | 1 | 10 | 1, 2, 5 | 100, 200 | 112 | 0.042 |

NOTES:

1. See Figure 2
- 2.

112.5

| Resistance (Ω) | Value Series | Available Tolerance (\pm %) | Available Temperature Coefficient ($\pm 10^{-6}/^{\circ}\text{C}$) |
|---------------------------|--|--------------------------------|--|
| $1 \leq R_n < 10$ | Any value in the resistance range to 3 significant figures | 2, 5 | 200 |
| $10 \leq R_n < 1\text{M}$ | | 1, 2, 5 | 100, 200 |
| $R_n \geq 1\text{M}$ | | 2, 5 | 200 |

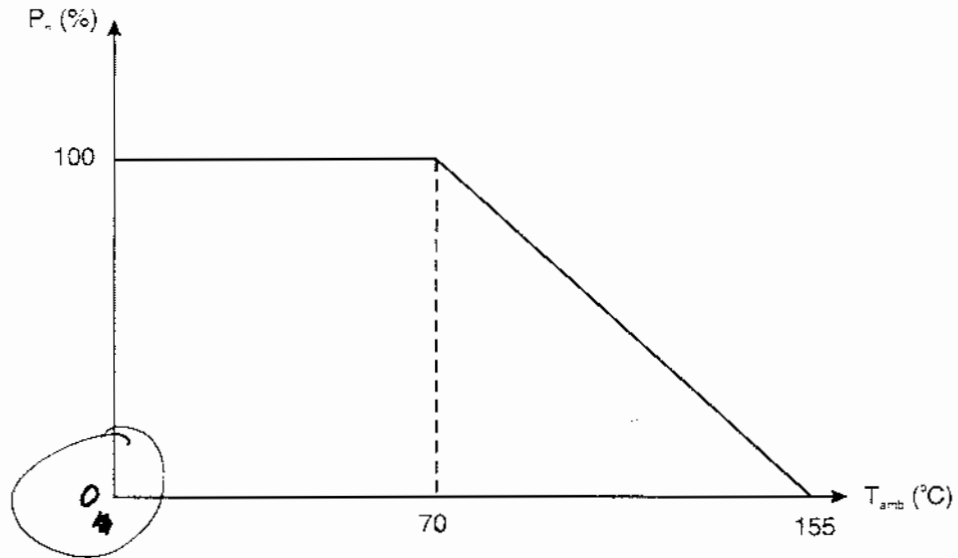
Table 1(b) - MAXIMUM RATINGS

| No. | Characteristics | Variant | Style | Symbol | Maximum Rating | Unit | Remarks |
|-----|-----------------------------|---------|----------------------|-----------|-------------------------|--------------------|-----------|
| 1 | Rated Dissipation | 01 | 0603 | P_n | 0.1 100 | W mW | Note 1 |
| | | 02 | 0805 | | 0.2 200 | | |
| | | 03 | 1216 1206 | | 0.25 250 | | |
| | | 04 | 2010 | | 0.5 500 | | |
| | | 05 | 2512 | | 0.8 800 | | |
| 2 | Limiting Element Voltage | 01 | 0603 | U_L | 50 | V | - |
| | | 02 | 0805 | | 100 | | |
| | | 03 | 1206 | | 200 | | |
| | | 04 | 2010 | | 300 | | |
| | | 05 | 2512 | | 300 | | |
| 3 | Rated Voltage | All | All | U_R | $\sqrt{P_n \times R_n}$ | V | Note 2 |
| 4 | Insulation Voltage | 01 | 0603 | U_I | 100 | V | - |
| | | 02 | 0805 | | 200 | | |
| | | 03 | 1206 | | 300 | | |
| | | 04 | 2010 | | 300 | | |
| | | 05 | 2512 | | 300 | | |
| 5 | Operating Temperature Range | All | All | T_{op} | -55 to +155 | $^{\circ}\text{C}$ | T_{amb} |
| 6 | Storage Temperature Range | All | All | T_{stg} | -55 to +155 | $^{\circ}\text{C}$ | - |
| 7 | Soldering Temperature | All | All | T_{sol} | +260 | $^{\circ}\text{C}$ | Note 3 |

NOTES:

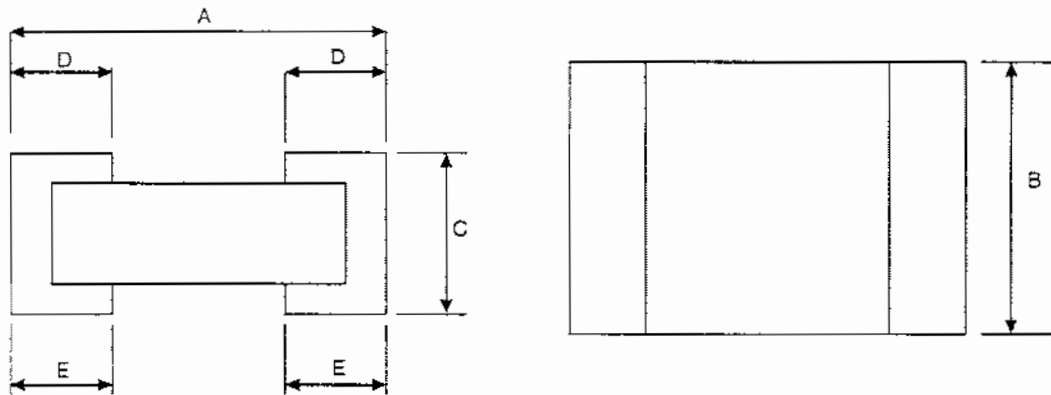
1. At $T_{amb} \leq +70^{\circ}\text{C}$. For derating at $T_{amb} > +70^{\circ}\text{C}$, see Figure 1.
2. Shall never exceed Limiting Element Voltage. R_n = rated resistance.
3. Duration 10 seconds maximum.

FIGURE 1- PARAMETER DERATING INFORMATION



Rated Dissipation versus Temperature

FIGURE 2 - PHYSICAL DIMENSIONS



| Variant | Style | Dimensions (mm) | | | | | | | |
|---------|-------|-----------------|------|------|------|------|------|------|------|
| | | A | | B | | C | | D, E | |
| | | Min | Max | Min | Max | Min | Max | Min | Max |
| 01 | 0603 | 1.36 | 1.68 | 0.72 | 0.98 | 0.38 | 0.53 | 0.25 | 0.51 |
| 02 | 0805 | 1.75 | 2.07 | 1.14 | 1.4 | 0.38 | 0.53 | 0.25 | 0.51 |
| 03 | 1206 | 2.89 | 3.21 | 1.47 | 1.73 | 0.38 | 0.53 | 0.25 | 0.51 |
| 04 | 2010 | 4.92 | 5.24 | 2.41 | 2.67 | 0.5 | 0.63 | 0.25 | 0.64 |
| 05 | 2512 | 6.19 | 6.51 | 2.93 | 3.32 | 0.5 | 0.63 | 0.25 | 0.64 |

4.5.3 ESCC Component Number

The ESCC Component Number shall be constituted and marked as follows:

Example : 4001⁰²⁶~~xxx~~01B

- Detail Specification Reference : 4001⁰²⁶~~xxx~~
- Component Type Variant Number : 01 (as required)
- Testing Level (B or C, as applicable)

4.5.4 Traceability Information

Each component shall be marked in respect of traceability information in accordance with the requirements of ESCC Basic Specification No. 21700.

4.6 ELECTRICAL MEASUREMENTS

4.6.1 Electrical Measurements at Room Temperature

The parameters to be measured at room temperature are scheduled in Table 2. Unless otherwise specified, measurements shall be performed at $T_{amb}=+22\pm 3^{\circ}\text{C}$.

4.6.2 Electrical Measurements at High and Low Temperatures

The parameters to be measured at high and low temperatures are scheduled in Table 3.

The distribution of the sample shall be as follows:

- 1/3 with lowest resistance value
- 1/3 with highest resistance value
- 1/3 with median resistance value or the critical resistance value if procured

of the procured range.

4.6.3 Circuits for Electrical Measurements (Figure 4)

Not applicable.

4.7 BURN-IN TESTS

4.7.1 Parameter Drift Values

The parameter drift values applicable to Burn-in are as specified in Table 4 of this specification. Unless otherwise stated, measurements shall be performed at $T_{amb}=+22\pm 3^{\circ}\text{C}$. The parameter drift values (Δ) applicable to the parameters scheduled shall not be exceeded. In addition to these drift value requirements for a given parameter, the appropriate limit values specified in Table 2 shall not be exceeded.

4.7.2 Conditions for Burn-in

The requirements for Burn-in are specified in Section 7 of ESCC Generic Specification No. 4001. The conditions for Burn-in shall be as specified in Table 5 of this specification.

After 168 (+12 -0) hours, the resistors shall be removed from the chamber and allowed to cool under normal atmospheric conditions for a minimum of 4 hours. They shall then be visually examined. There shall be no evidence of damage and marking shall still be legible.

Table 6 - MEASUREMENTS AND INSPECTIONS ON COMPLETION OF ENVIRONMENTAL TESTS AND AT INTERMEDIATE POINTS AND ON COMPLETION OF ENDURANCE TESTING

| No. | ESCC Generic Spec. No. 4001 | | Measurements and Inspections | | Symbol | Limits | | Unit | |
|-----|--|---|---|---|---|---------------------------------|---------------|----------------------|----------------|
| | Environmental and Endurance Tests (Note 1) | Test Methods and Conditions | Identification | Conditions | | Min | Max | | |
| 01 | Overload | Para. 9.1 and Paras 4.2.2 and 4.2.4 of this spec. | <u>Initial Measurements</u> Chart IV Resistance | Table 2 Item 1 After a recovery period of 1-2 hrs No evidence of damage and marking legible | R _A | Record Values | | Ω | |
| | | | <u>Final Measurements</u> Visual Examination | | | | | | - |
| | | | Chart II Resistance Chart IV Resistance Change | Table 2 item 1 Table 2 Item 1 | R _A ΔR _A /R _A | Table 2 Item 1 Note 4 | Ω % | | |
| 02 | Seal Test (Hermetically Sealed only) | Para. 9.3 | Not applicable | - | - | - | - | - | |
| 03 | Insulation Resistance (Insulated only) | Para. 9.6 | <u>Final Measurements</u> Insulation Resistance | Para. 9.6.2 of ESCC 4001 (Note 2) | R _i | 1000 | - | MΩ | |
| 04 | Temperature Coefficient | Para. 9.7 Procedure I | Temperature Coefficient | Para. 9.5.1 of ESCC 4001 | TC | -100 -200 | +100 +200 | 10 ⁻⁶ /°C | |
| 05 | Voltage Proof | Para. 9.8.2 | <u>During test</u> | 1.4 x UT for 60 ± 5 sec, Note 3 | - | - | - | - | |
| | | | Visual Examination | No breakdown or flashover | - | - | - | - | |
| 06 | Solderability | Para. 9.9 <i>Procedure I</i> | <u>Initial Measurements</u> Resistance | After Drying Table 2 item 1 24 ± 4hrs after soldering | R _A | Record Values | | Ω | |
| | | | <u>Final Measurements</u> Resistance Change | | | | | | Table 2 Item 1 |
| | | | - | - | - | - | - | - | - |
| 07 | Robustness of Terminations | Para. 9.10.2 | - | After Mounting | - | - | - | - | |
| | | | Adhesion | <u>Initial Measurements</u> Resistance | Table 2 item 1 | R _A | Record Values | | Ω |
| | | | | <u>Final Measurements</u> Resistance Change | Table 2 Item 1 | ΔR _A /R _A | Note 5 | | % |
| | | | | Visual Examination | No damage, lifting, cracking or dry joints | - | - | - | - |
| | | | Bend Strength of End Plate Facing | <u>Initial Measurements</u> Resistance | Table 2 Item 1 Board in bent position | R _A | Record Values | | Ω |
| | | | | Resistance Change | Table 2 Item 1 | ΔR _A /R _A | Note 5 | | % |
| | Visual Examination | No damage, lifting, cracking or dry joints | - | - | - | - | | | |

| No. | ESCC Generic Spec. No. 4001 | | Measurements and Inspections | | Symbol | Limits | | Unit |
|-----|--|--|---|---|------------------|---------------|-----|-----------|
| | Environmental and Endurance Tests (Note 1) | Test Methods and Conditions | Identification | Conditions | | Min | Max | |
| 08 | Resistance to Soldering Heat | Para. 9.11 Procedure I | <u>Initial Measurements</u> Resistance | After Drying Table 2 Item 1 | R_A | Record Values | | Ω |
| | | | <u>Final Measurements</u> Visual Examination | No evidence of damage and marking legible | - | - | - | - |
| | | | Resistance Change | Table 2 Item 1 | $\Delta R_A/R_A$ | Note 4 | | % |
| 09 | Rapid Change of Temperature | Para. 9.12 | <u>Initial Measurements</u> Resistance | Table 2 item 1 | R_A | Record Values | | Ω |
| | | | <u>Final Measurements</u> | After a recovery period of 1-2 hrs | - | - | - | - |
| | | | Visual Examination | No evidence of damage | - | - | - | - |
| | | | Resistance Change | Table 2 Item 1 | $\Delta R_A/R_A$ | Note 5 | | % |
| 10 | Vibration | Para. 9.13 and Paras 4.2.4 and 4.2.5 of this spec. | Not applicable | - | - | - | - | - |
| 11 | Climatic Sequence | Para. 9.14 Procedure I | <u>Initial Measurements</u> Resistance | After Drying Table 2 Item 1 | R_A | Record Values | | Ω |
| | | | <u>Final Measurements</u> | Following completion of DC load test and after a recovery period of 1-2 hrs | - | - | - | - |
| | | | Visual Examination | No evidence of damage and marking legible | - | - | - | - |
| | | | Insulation Resistance | Para. 9.6 of ESCC 4001, Note 2 | R_i | 1000 | - | $M\Omega$ |
| | | | Resistance Change | Table 2 Item 1 | $\Delta R_A/R_A$ | Note 6 | | % |
| 12 | Operating Life | Para. 9.15 Chart IV | <u>Initial Measurements</u> Resistance | Table 2 Item 1 | R_A | Record Values | | Ω |
| | | | <u>Intermediate Measurements</u> (1000 hrs) | After a recovery period of 1-2 hrs | - | - | - | - |
| | | | Visual Examination | No evidence of damage | - | - | - | - |
| | | | Resistance Change | Table 2 Item 1 | $\Delta R_A/R_A$ | Note 6 | | % |
| | | | <u>Final Measurements</u> (2000 hrs) | After a recovery period of 1-2 hrs | - | - | - | - |
| | | | Visual Examination | No evidence of damage | - | - | - | - |
| | | | Resistance Change | Table 2, Item 1 | $\Delta R_A/R_A$ | Note 7 | | % |
| | | | Insulation Resistance | Para. 9.6 of ESCC 4001, Note 2 | R_i | 1000 | - | $M\Omega$ |

| No. | ESCC Generic Spec. No. 4001 | | Measurements and Inspections | | Symbol | Limits | | Unit |
|-----|--|-----------------------------|---|---|--|---|---|------|
| | Environmental and Endurance Tests (Note 1) | Test Methods and Conditions | Identification | Conditions | | Min | Max | |
| | | Para. 9.15 Chart V | <u>Initial Measurements</u> Resistance <u>Final Measurements</u> (1000 hrs) Visual Examination Resistance Change Insulation Resistance | Table 2 Item 1 After a recovery period of 1-2 hrs No evidence of damage Table 2 Item 1 Para. 9.6 of ESCC 4001, Note 2 | R_A - $\Delta R_A/R_A$ R_i | Record Values - Note 6 1000 - | Ω - % $M\Omega$ | |
| 13 | High Temperature Storage | Para. 9.16 | <u>Initial Measurements</u> Resistance <u>Intermediate</u> <u>Measurements</u> (1000 hrs) Visual Examination Resistance Change <u>Final Measurements</u> (2000 hrs) Visual Examination Resistance Change Insulation Resistance | Table 2 Item 1 After a recovery period of 1-2 hrs No evidence of damage Table 2 Item 1 After a recovery period of 1-2 hrs No evidence of damage Table 2 Item 1 Para. 9.6 of ESCC 4001, Note 2 | R_A - $\Delta R_A/R_A$ - $\Delta R_A/R_A$ R_i | Record Values - Note 6 - - Note 7 1000 - | Ω - % - % $M\Omega$ | |
| 14 | Permanence of Marking | Para. 9.19 | - | - | - | - | - | - |

NOTES:

1. The tests in this Table refer to either Chart IV or V and shall be used as applicable.

2. Test Voltage: $V_T = 100V$

3. For value of U_I see Table 1(b) Item 4.

4. $\Delta R_A/R_A$ limit: $\pm(0.5 + 0.05\Omega \times 100/R_n)\%$

5. $\Delta R_A/R_A$ limit: $\pm(0.25 + 0.05\Omega \times 100/R_n)\%$

6. $\Delta R_A/R_A$ limit: $\pm(1 + 0.05\Omega \times 100/R_n)\%$

7. $\Delta R_A/R_A$ limit: $\pm(1.5 + 0.05\Omega \times 100/R_n)\%$

$\leftarrow \pm(0.5 + 0.05\Omega \times 100/R_n)\%$
 $\leftarrow \pm(0.25 + 0.05\Omega \times 100/R_n)\%$
 $\leftarrow \pm(1 + 0.05\Omega \times 100/R_n)\%$
 $\leftarrow \pm(1.5 + 0.05\Omega \times 100/R_n)\%$

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